

ABSTRACT OF THE DISCLOSURE

A method and apparatus for performing a built-in self-test (“BIST”) on an integrated circuit device are disclosed. A BIST controller comprises a BIST engine and a register. The BIST engine is capable of executing a built-in self-test and storing the results thereof, wherein the results include an indication of whether an executed built-in self-test is completed. The register is capable of storing the results of the executed built-in self-test, including the indication. A method for performing a built-in self-test comprises performing a BIST, including generating a indication of whether the built-in self-test is completed, and storing the indication.